

Notice of References Cited	Application/Control No. 10/762,995	Applicant(s)/Patent Under Reexamination LIEBENOW, FRANK	
	Examiner Scott Sun	Art Unit 2182	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0001083 A1	05-2001	Helot, Jacques H.	439/131
*	B	US-2002/0043960 A1	04-2002	Janik, Craig M.	320/128
*	C	US-2002/0119800 A1	08-2002	Jaggers et al.	455/550
*	D	US-2003/0115395 A1	06-2003	Karcher et al.	710/303
*	E	US-2003/0129978 A1	07-2003	Akiyama et al.	455/426
*	F	US-2003/0156012 A1	08-2003	Omidi et al.	340/310.01
*	G	US-2004/0088465 A1	05-2004	Bianchi, Mark John	710/303
*	H	US-2005/0015805 A1	01-2005	Iwamura, Ryuichi	725/079
*	I	US-6,913,477 B2	07-2005	Dayan et al.	439/188
*	J	US-2001/0042150	11-2001	Moroz et al.	710/103
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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